

Research Infusion: ODC for Microwave Subsystem Controller

Robyn Lutz, Leslie Manalo, Tuan Do, Scott Morgan
JPL/Caltech

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Overview: ODC for Microwave (UWV) Subsystem Controller (USC)

- **Controller automates monitoring and controlling of equipment for up/downlink operation and calibration of the Deep Space Network antennas**
- **224 Internal Anomaly Reports (IARs) generated during testing**
- **Four ODC attributes used: Activity, Trigger, Target, Type**

Process: ODC for Microwave (UWV) Subsystem Controller (USC)

- **ODC customization** of definitions for Microwave (UWV) Subsystem Controller (USC) IARs
 - Customized by project (Leslie Manalo)
 - Materials, advice, review of draft provided by ODC researchers (Tuan Do & Robyn Lutz)
- **ODC classification of anomalies**
 - Classified by project
 - Feedback & questions answered by ODC researchers
- **ODC analysis of anomalies**
 - Pivot tables created by ODC researcher (Tuan Do)
 - Interpretation of results by all
- **Report produced**
 - Co-written by Leslie Manalo & Tuan Do
 - Reviewed by all

Recommendations: ODC for Microwave (UWV) Subsystem Controller (USC)

- Do ODC on the next round of USC and compare against this year's analysis to use as a benchmark.
- Implement the ODC subsets described in APPENDIX 1 in Harvest so that testers and developers can classify the IARs themselves. This would allow a more effective means of using ODC at a later date.
- Expand on the information in the IARs so that it is easier to classify IARs using the ODC.
- Experiment with earlier review of the DSS tables (prior to testing) to see if this brings down the number of IARs.
- Examine how many IARs with Visual Inspection as their Trigger have "text/labels that need to be changed". If the number is high, review the text and labels prior to build testing.
- Examine the subset of IARs with Monitor Capability as the Trigger and either Assignment/Initialization or DSS Tables as the Type of the correction, to see if these can be prevented by earlier analysis/inspection.